



PUNYASHLOK AHILYADEVI HOLKAR SOLAPUR UNIVERSITY, SOLAPUR

Electronics (IOT)
Semester
EXAM MAR./APR-2025

EXAM OF 2024 SEMESTER PATTERN EXAMINATION

REVISED FINAL PROGRAM OF M.SC. ELECTRONICS (IOT) SEMESTER – I & II MAR./APR.- 2025 EXAMINATION TO BE HELD IN MAY.-2025

1. Student should see their Seat No. and Name in the Name list and mistakes if any should be communicate to this office immediately. All candidates are requested to confirm their Examination Seat No. as well as place of examination on the Notice Board of the University/College mentioned below at least two days before the date of Examination. The candidate should write correct Seat No. on each answer book. If candidate writes wrong Seat No. on answer Book the performance of such subject will not be considered.
2. Candidate are requested to be present at their respective places of the Examination **FIFTEEN MINUTES** before the time starting of the first paper and **TEN MINUTES** before the time starting of each subsequent paper. Candidates are forbidden to take any book or paper into the Examination Hall.
3. **Important Note:** Code Numbers given in the Bracket are Computer Code of respective Subjects, Students should mention these Code Numbers on Answer Books with Name of the Subject. Also write these Code Numbers on JSR (Junior Supervisor Report) and related documents.
4. All the Candidates are asked to follow the timely instructions given by University in accordance with the examinations methodology.
5. As per the Rights of Person with Disabilities Act-2016 the persons with Disabilities are given 20 minutes extra for one per hour for the Online/Offline exam . (केंद्र शासनाच्या अपंग व्यक्ती अधिकार अधिनियम २०१६ मधील तरतूदीनुसार अपंग विद्यार्थ्यांना ऑनलाईन व ऑफलाईन परीक्षेमध्ये सर्वसाधारण विद्यार्थ्यांपेक्षा १ तासाला कमोतकमी २० मिनीट इतका वेळ वाढवून देण्यास सर्वानुमते मान्यता देण्यात आली.)

Sr. No.	Center	College Abbreviation	Place
1	Barshi	SBZ	Shriman Bhausahab Zadbuke Mahavidyalaya, Barshi

ELECTRONICS (IOT) Sem – I (New w.e.f. June 2023) (NEP CBCS Pattern-2023)			
Day &Date	Paper No.	Sr. No.	Subject Time: 3:00 p.m.to 5:30p.m
Thursday 15/05/2025	DSC 1-1	1	Hardware, Programming and IDE tools- AVR & PIC Series (2315101)
Saturday 17/05/2025	DSC 1-2	2	Sensors and Actuators (2315102)
Monday 19/05/2025	DSE-1-3	3	A) Programming with C and C++ (2315107) OR
		4	B) Modern Communication System ((2315108) OR
		5	C) Electronics System Design (2315109)
Saturday 24/05/2025	RM	6	Research Methodology (2315103)

ELECTRONICS (IOT) Sem – II (New w.e.f. June 2023) (NEP CBCS Pattern-2023)			
Day &Date	Paper No.	Sr. No.	Subject Time: 3:00 p.m.to 5:30p.m
Wednesday 14/05/2025	DSC 1-3	7	Interfacing & Embedded System Design using – AVR & PIC Microcontrollers (2315201)
Friday 16/05/2025	DSC 1-4	8	Fundamentals of Internet of Things (2315202)
Tuesday 20/05/2025	DSE-1-3	9	A) Application Development using Arduino, NodeMCU & LORA (2315207)
		10	OR
		11	B) Cellular Data Communication (2315208)
			OR
			C) Antenna and Wave Propagation (2315209)

ELECTRONICS (IOT) Sem – III (New w.e.f. June 2024) (NEP CBCS Pattern-2023)			
Day &Date	Paper No.	Sr. No.	Subject Time: 11:00 a.m.to 1:30p.m
Thursday 15/05/2025	DSC-1-5	12	Introduction to Raspberry Pi (2315301)
Saturday 17/05/2025	DSC-1-6	13	Fundamentals of Sensor Networks (2315302)
Monday 19/05/2025	DSE-1-3	14	A) Programming in Python and Application Development (2315306)
		15	OR
		16	B) Introduction to Cloud Computing (2315307)
			OR
			C) IoT Platform and System Design (2315308)

ELECTRONICS (IOT) Sem – IV (New w.e.f. NOV. 2024) (NEP CBCS Pattern-2023)			
Day & Date	Paper No.	Sr. No.	Subject Time: 11:00 a.m.to 1:30p.m
Wednesday 14/05/2025	DSC-1-7	17	Data Analytics & Industrial IoT (2315401)
Friday 16/05/2025	DSC-1-8	18	Advanced Wireless Sensor Networks(2315402)
Tuesday 20/05/2025	DSE-1-4	19	A) Java Programming For Mobile Application Development (2315406) OR
		20	B) Advanced Java Programming (2315407) OR
		21	C) Mobile Computing (2315408)

Please visit – sus.ac.in

Ref No.: PAHSUS/EXAM/TIME-TABLE/2025/844

Date :- 06/05/2025

Sd/-
Director
Board of Examinations and Evaluation